

MICRON.100C1

PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

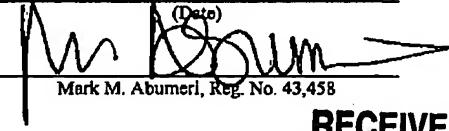
Appl. No. : 10/608,913  
 Applicant : Craig A. Hickman  
 Filed : June 26, 2003  
 For : DEVICE AND METHOD OF  
       CORRECTING EXPOSURE  
       DEFECTS IN  
       PHOTOLITHOGRAPHY  
 Group Art Unit : 2851  
 Examiner : Rodney Evan Fuller  
 Attny Docket No. : MICRON.100C1  
 Customer No. : 20,995

Confirmation No. 7050

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July 22, 2004


  
 (Date)  
 Mark M. Abumeri, Reg. No. 43,458

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AMENDMENT AND RESPONSE TO FINAL OFFICE ACTION

Commissioner for Patents  
 P.O. Box 1450  
 Alexandria, VA 22313-1450

**OFFICIAL**

Dear Sir:

In response to the final Office Action of June 10, 2004, the Applicant submits the following amendment and remarks for consideration in connection with the above-captioned application.

**Amendments to the Claims** are reflected in the listing of claims, which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 7 of this paper.

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July 22, 2004

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Docket No.: MICRON.100C1

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## AMENDMENT / RESPONSE TRANSMITTAL

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Mark M. Abumeri, Reg. No. 43,458

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Sir:

Transmitted herewith for filing in the above-identified application are the following enclosures:

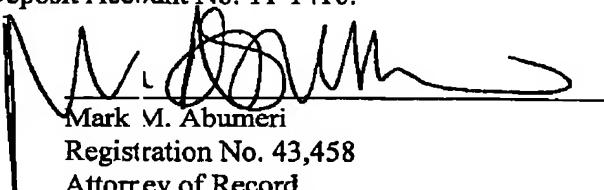
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